Abstracts

Analysis of Microwave Circuit for Characterization of Negative-Conductance Devices by Transients (Letters)

K. Tomizawa, T. Hariu and H. Hartnagel. "Analysis of Microwave Circuit for Characterization of Negative-Conductance Devices by Transients (Letters)." 1973 Transactions on Microwave Theory and Techniques 21.9 (Sep. 1973 [T-MTT]): 596-598.

The assumptions required for the transient method of measuring Gunn-diode conductance are shown to be valid if either the diode susceptance or the characteristic admittance of the resonator transmission line are larger than the modulus of the negative conductance of the device.

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